Notice of References Cited Application/Control No. 10/518,246 Examiner Mark L. Berch Applicant(s)/Patent Under Reexamination SHIPTON ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0004128 A1	01-2003	Bountra et al.	514/263.23
*	В	US-2003/0004126 A1	01-2003	Bountra et al.	514/263.23
*	С	US-2003/0008842 A1	01-2003	Bountra et al.	514/263.23
*	D	US-2003/0004127 A1	01-2003	Bountra et al.	514/263.23
*	Ε	US-2003/0018008 A1	01-2003	Bountra et al.	514/263.23
*	F	US-2003/0004129 A1	01-2003	Bountra et al.	514/263.23
*	G	US-6,677,316 B2	01-2004	Bays et al.	514/263.23
*	Н	US-2005/0176949 A1	08-2005	Berry et al.	536/027.3
*	1	US-2004/0180908 A1	09-2004	King, Paula	514/263.2
*	J	US-2002/0198170	12-2002	Bountra et al.	514/46
*	К	US-2004/0167092	08-2004	Bountra et al.	514/046
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N			-		
	0					
	P					
	Ø		-			
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.